

Application/Control No.	Applicant(s)/Patent under Reexamination
10/568,947	MUTO ET AL.
Examiner	Art Unit
Hai H. Huynh	3747

SEARCHED				
Class	Subclass	Date	Examiner	
123	399	4/4/2007	ннн	
123	350	4/4/2007	ннн	
123	90.11	4/4/2007	ННН	
123	90.15	4/4/2007	ннн	
123	90.16	4/4/2007	ннн	
123	90.17	4/4/2007	ннн	
123	568.11	4/4/2007	ннн	
123	568.14	4/4/2007	ннн	
73	117.3	4/4/2007	ннн	
73	118.2	4/4/2007	ннн	
701	106	4/4/2007	ннн	
701	110	4/4/2007	ннн	
701	115	4/4/2007	ннн	
update	search	9/12/2007	ннн	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
above	search	9/12/2007	ннн	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East	4/4/2007	ннн	
	9/12/2007	ннн	
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